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**Antares and Aehr Test Systems Partner to  
Address High-Power Test During Burn-in Market**

*Partnership Comes as Antares Delivers iSocket Individual Thermal-Management System to the Israeli Test House (ITH) for High-Power Devices on an Aehr Test Systems MAX4-200 TDBI system*

*System is first of its kind in Israel*

PHOENIX, AZ and FREMONT, CA, July 14, 2008 – Antares and Aehr Test Systems, two leading suppliers of semiconductor test equipment, announced today that they have agreed to work together to address the establishment of a strategic partnership to jointly pursue the high-power, Individual Temperature Control (ITC), Test During Burn-in (TDBI) market for packaged devices that dissipate up to 75W per device.

“High Power TDBI is a rapidly growing market that is underserved today,” said Rhea Posedel, chairman and chief executive officer of Aehr Test Systems.

“By combining our individual companies’ expertise, we will be able to provide a complete solution to those customers who need this capability,” said Matt Bergeron, chief executive officer of Antares.

“Our two companies have been working together informally for some time now on several successful projects, so it makes sense to go ahead and formalize the relationship,” Posedel said.

“The two companies bring together the best of both worlds. Antares brings expertise in ITC, and Aehr brings integrated TDBI system level expertise. We are both very excited about the new markets this initiative opens for us,” said Mr. Bergeron.

The partnership between the companies comes as Antares and Aehr expand their presence in Israel. The Israeli test house (ITH) will soon take delivery of an iSocket system integrated into a chamber designed by Aehr Test Systems that will be used for independent thermal management of high-power (75W) devices.

The system will effectively give ITH the ability to efficiently burn-in a mixed lot of both high- and low-power devices under test (DUTs) in the same system, according to Chris Lopez, Antares’ manager of thermal solutions.

“The system essentially gives ITH a flexible and cost-effective burn-in solution with a quick turnaround to implementation,” Lopez said.

### **About Aehr Test Systems**

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing memory and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX, MTX and MAX systems and the DiePak(r) carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at <http://www.aehr.com>.

### **About Antares Advanced Test Technologies**

Antares Advanced Test Technologies is reducing the cost of semiconductor test by concentrating on high-sensitivity areas such as yield and the integration of test disciplines, focusing on customer support, delivering innovative technologies and offering a single point of contact for semiconductor test cell requirements, including burn-in sockets, test sockets, ATE consumables and thermal management solutions. Antares is headquartered in Vancouver, Wash. and has design, development and

manufacturing locations in Suzhou, China; Yokohama, Japan; Phoenix and Gilbert, Ariz.; and Milpitas and Santa Clara, Calif. <http://www.antaes-att.com/>

### **About ITH – Israeli Test House**

As the only Test House in Israel, ITH ([www.ith.co.il](http://www.ith.co.il)) has supported the Semiconductor industry for more than 12 years with Test, Reliability and Failure Analysis services. ITH combines the experience of hundreds of projects with state-of-the-art ATE and Qualification equipment, providing the customer with the best available solutions for all VLSI back-end needs. With the new system, ITH will support many local and international customers with High Power Burn-In solutions for their high end and high power devices (up to 70W). The upgrade of the Burn-In capabilities will place ITH at the front of the Test Houses in the world with the leading Qualification solutions.

### **Safe Harbor Statement**

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance for products developed by Aehr Test and Antares. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the high-power TDBI technology; acceptance by customers of the high-power TDBI systems shipped upon receipt of a purchase order; and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. Aehr Test Systems disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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